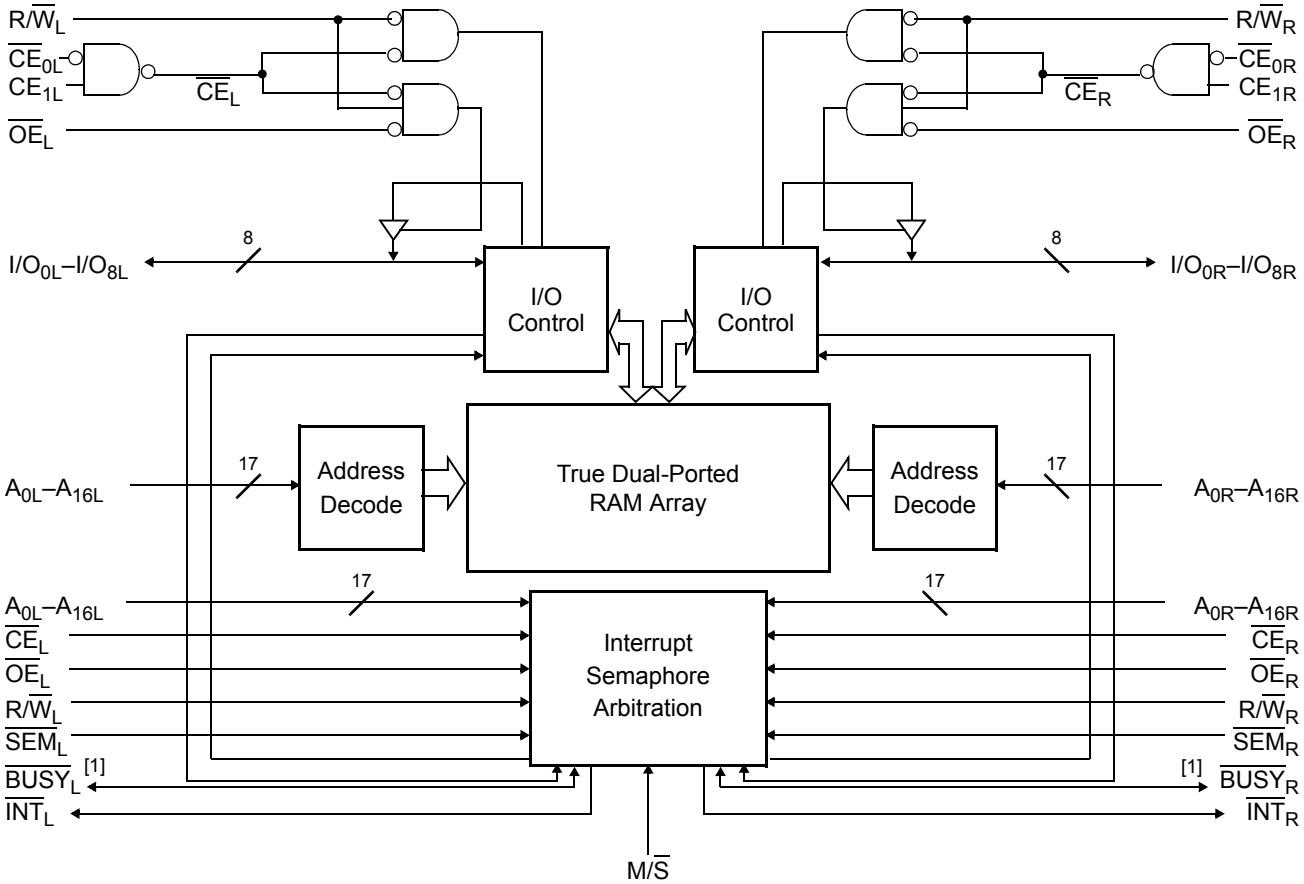
CY7C009V

3.3 V, 128K × 8 Dual-Port Static RAM

Features

- True dual-ported memory cells which allow simultaneous access of the same memory location
- 128K × 8 organization (CY7C009)
- 0.35-micron CMOS for optimum speed/power
- High-speed access: 15/20/25 ns
- Low operating power
  - Active: I_{CC} = 115 mA (typical)
  - Standby: I_{SB3} = 10 µA (typical)
- Fully asynchronous operation
- Automatic power-down
- Expandable data bus to 16 bits or more using Master/Slave chip select when using more than one device
- On-chip arbitration logic
- Semaphores included to permit software handshaking between ports
- $\overline{INT}$ flag for port-to-port communication
- Dual chip enables
- Pin select for Master or Slave
- Commercial and industrial temperature ranges
- Available in 100-pin TQFP
- Pb-free packages available

Logic Block Diagram



Note
1. $\overline{BUSY}$ is an output in master mode and an input in slave mode.

Functional Description

The CY7C009V is a low-power CMOS 64K, 128K × 8 dual-port static RAM. Various arbitration schemes are included on the devices to handle situations when multiple processors access the same piece of data. Two ports are provided permitting independent, asynchronous access for reads and writes to any location in memory. The devices can be utilized as standalone 8/9-bit dual-port static RAMs or multiple devices can be combined in order to function as a 16/18-bit or wider master/slave dual-port static RAM. An M/$\overline{S}$ pin is provided for implementing 16/18-bit or wider memory applications without the need for separate master and slave devices or additional discrete logic. Application areas include interprocessor/multiprocessor designs, communications status buffering, and dual-port video/graphics memory.

Each port has independent control pins: chip enable ($\overline{CE}$), read or write enable (R/$\overline{W}$), and output enable ($\overline{OE}$). Two flags are provided on each port ($\overline{BUSY}$ and $\overline{INT}$). $\overline{BUSY}$ signals that the port is trying to access the same location currently being accessed by the other port. The interrupt flag ($\overline{INT}$) permits communication between ports or systems by means of a mail box. The semaphores are used to pass a flag, or token, from one port to the other to indicate that a shared resource is in use. The semaphore logic is comprised of eight shared latches. Only one side can control the latch (semaphore) at any time. Control of a semaphore indicates that a shared resource is in use. An automatic power-down feature is controlled independently on each port by a chip select ($\overline{CE}$) pin.

The CY7C009V is available in 100-pin Thin Quad Plastic Flatpacks (TQFP).

For a complete list of related documentation, click here.

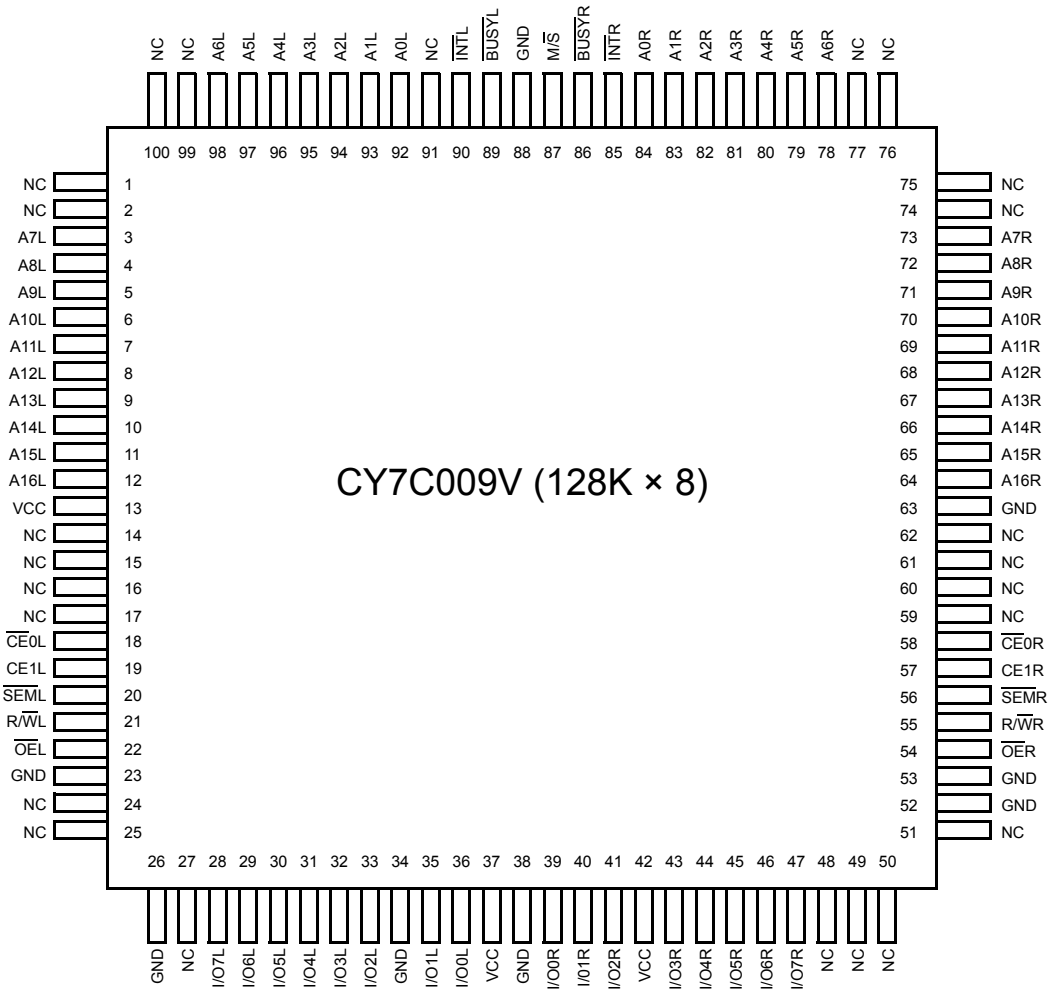
Contents

Selection Guide

Description	CY7C009V –15	CY7C009V –20	CY7C009V –25	Unit
Maximum access time	15	20	25	ns
Typical operating current	125	120	115	mA
Typical standby current for I_{SB1} (both ports TTL level)	35	35	30	mA
Typical standby current for I_{SB3} (both ports CMOS level)	10	10	10	µA

Pin Configurations

Figure 1. 100-pin TQFP pinout (Top View)



Pin Definitions

Left Port	Right Port	Description
$\overline{CE}_{0L}$, CE_{1L}	$\overline{CE}_{0R}$, CE_{1R}	Chip enable ($\overline{CE}$ is LOW when $\overline{CE}_0 \le V_{IL}$ and $CE_1 \ge V_{IH}$)
$R/\overline{W}_L$	$R/\overline{W}_R$	Read/Write enable
$\overline{OE}_L$	$\overline{OE}_R$	Output enable
A_{0L}–A_{16L}	A_{0R}–A_{16R}	Address
I/O_{0L}–I/O_{7L}	I/O_{0R}–I/O_{7R}	Data bus input/output
$\overline{SEM}_L$	$\overline{SEM}_R$	Semaphore enable
$\overline{INT}_L$	$\overline{INT}_R$	Interrupt flag
$\overline{BUSY}_L$	$\overline{BUSY}_R$	Busy flag
$M/\overline{S}$		Master or slave select
V_{CC}		Power
GND		Ground
NC		No Connect

Architecture

The CY7C009V consists of an array of 128K words of 8 bits each of dual-port RAM cells, I/O and address lines, and control signals ($\overline{CE}$, $\overline{OE}$, R/$\overline{W}$). These control pins permit independent access for reads or writes to any location in memory. To handle simultaneous writes/reads to the same location, a $\overline{BUSY}$ pin is provided on each port. Two interrupt ($\overline{INT}$) pins can be utilized for port-to-port communication. Two semaphore ($\overline{SEM}$) control pins are used for allocating shared resources. With the M/$\overline{S}$ pin, the devices can function as a master ($\overline{BUSY}$ pins are outputs) or as a slave ($\overline{BUSY}$ pins are inputs). The devices also have an automatic power-down feature controlled by $\overline{CE}$. Each port is provided with its own output enable control ($\overline{OE}$), which allows data to be read from the device.

Functional Overview

Write Operation

Data must be set up for a duration of t_{SD} before the rising edge of R/$\overline{W}$ in order to guarantee a valid write. A write operation is controlled by either the R/$\overline{W}$ pin (see Write Cycle No. 1 waveform) or the $\overline{CE}$ pin (see Write Cycle No. 2 waveform). Required inputs for non-contention operations are summarized in Table 1.

If a location is being written to by one port and the opposite port attempts to read that location, a port-to-port flowthrough delay must occur before the data is read on the output; otherwise the data read is not deterministic. Data will be valid on the port t_{DDD} after the data is presented on the other port.

Table 1. Non-Contending Read/Write

Inputs				Outputs	Operation
$\overline{CE}$	R/$\overline{W}$	$\overline{OE}$	$\overline{SEM}$	I/O_0–I/O_8	
H	X	X	H	High Z	Deselected: Power-down
H	H	L	L	Data out	Read data in semaphore flag
X	X	H	X	High Z	I/O lines disabled
H	⎍	X	L	Data in	Write into semaphore flag
L	H	L	H	Data out	Read
L	L	X	H	Data in	Write
L	X	X	L		Not allowed

Read Operation

When reading the device, the user must assert both the $\overline{OE}$ and $\overline{CE}$ pins. Data will be available t_{ACE} after $\overline{CE}$ or t_{DOE} after $\overline{OE}$ is asserted. If the user wishes to access a semaphore flag, then the $\overline{SEM}$ pin must be asserted instead of the $\overline{CE}$ pin, and $\overline{OE}$ must also be asserted.

Interrupts

The upper two memory locations may be used for message passing. The highest memory location (1FFFF for the CY7C009) is the mailbox for the right port and the second-highest memory location (1FFFE for the CY7C009) is the mailbox for the left port. When one port writes to the other port's mailbox, an interrupt is generated to the owner. The interrupt is reset when the owner reads the contents of the mailbox. The message is user defined.

Each port can read the other port's mailbox without resetting the interrupt. The active state of the busy signal (to a port) prevents the port from setting the interrupt to the winning port. Also, an active busy to a port prevents that port from reading its own mailbox and, thus, resetting the interrupt to it.

If an application does not require message passing, do not connect the interrupt pin to the processor's interrupt request input pin.

The operation of the interrupts and their interaction with Busy are summarized in Table 2.

Table 2. Interrupt Operation Example (assumes $\overline{BUSY}_L$ = $\overline{BUSY}_R$ = HIGH)

Function	Left Port					Right Port				
	$R/\overline{W}_L$	$\overline{CE}_L$	$\overline{OE}_L$	$A_{0L–16L}$	$\overline{INT}_L$	$R/\overline{W}_R$	$\overline{CE}_R$	$\overline{OE}_R$	$A_{0R–16R}$	$\overline{INT}_R$
Set Right $\overline{INT}_R$ Flag	L	L	X	1FFFF	X	X	X	X	X	L[2]
Reset Right $\overline{INT}_R$ Flag	X	X	X	X	X	X	L	L	1FFFF	H[3]
Set Left $\overline{INT}_L$ Flag	X	X	X	X	L[3]	L	L	X	1FFFE	X
Reset Left $\overline{INT}_L$ Flag	X	L	L	1FFFE	H[2]	X	X	X	X	X

Busy

The CY7C009V provide on-chip arbitration to resolve simultaneous memory location access (contention). If both ports' $\overline{CE}$s are asserted and an address match occurs within t_{PS} of each other, the busy logic will determine which port has access. If t_{PS} is violated, one port will definitely gain permission to the location, but it is not predictable which port will get that permission. $\overline{BUSY}$ will be asserted t_{BLA} after an address match or t_{BLC} after $\overline{CE}$ is taken LOW.

Master/Slave

A $M/\overline{S}$ pin is provided in order to expand the word width by configuring the device as either a master or a slave. The $\overline{BUSY}$ output of the master is connected to the $\overline{BUSY}$ input of the slave. This will allow the device to interface to a master device with no external components. Writing to slave devices must be delayed until after the $\overline{BUSY}$ input has settled (t_{BLC} or t_{BLA}), otherwise, the slave chip may begin a write cycle during a contention situation. When tied HIGH, the $M/\overline{S}$ pin allows the device to be used as a master and, therefore, the $\overline{BUSY}$ line is an output. $\overline{BUSY}$ can then be used to send the arbitration outcome to a slave.

Semaphore Operation

The CY7C009V provide eight semaphore latches, which are separate from the dual-port memory locations. Semaphores are used to reserve resources that are shared between the two ports.The state of the semaphore indicates that a resource is in use. For example, if the left port wants to request a given resource, it sets a latch by writing a zero to a semaphore location. The left port then verifies its success in setting the latch by reading it. After writing to the semaphore, $\overline{SEM}$ or $\overline{OE}$ must be deasserted for t_{SOP} before attempting to read the semaphore. The semaphore value will be available t_{SWRD} + t_{DOE} after the rising edge of the semaphore write. If the left port was successful (reads a zero), it assumes control of the shared resource, otherwise (reads a one) it assumes the right port has control and continues to poll the semaphore. When the right side has relinquished control of the semaphore (by writing a one), the left side will succeed in gaining control of the semaphore. If the left side no longer requires the semaphore, a one is written to cancel its request.

Semaphores are accessed by asserting $\overline{SEM}$ LOW. The $\overline{SEM}$ pin functions as a chip select for the semaphore latches ($\overline{CE}$ must remain HIGH during $\overline{SEM}$ LOW). $A_{0–2}$ represents the semaphore address. $\overline{OE}$ and $R/\overline{W}$ are used in the same manner as a normal memory access. When writing or reading a semaphore, the other address pins have no effect.

When writing to the semaphore, only I/O_0 is used. If a zero is written to the left port of an available semaphore, a one will appear at the same semaphore address on the right port. That semaphore can now only be modified by the side showing zero (the left port in this case). If the left port now relinquishes control by writing a one to the semaphore, the semaphore will be set to one for both sides. However, if the right port had requested the semaphore (written a zero) while the left port had control, the right port would immediately own the semaphore as soon as the left port released it. Table 3 on page 7 shows sample semaphore operations.

When reading a semaphore, all data lines output the semaphore value. The read value is latched in an output register to prevent the semaphore from changing state during a write from the other port. If both ports attempt to access the semaphore within t_{SPS} of each other, the semaphore will definitely be obtained by one side or the other, but there is no guarantee which side will control the semaphore.

Notes
2. If $\overline{BUSY}_L$ = L, then no change.
3. If $\overline{BUSY}_R$ = L, then no change.

Table 3. Semaphore Operation Example

Function	I/O_0–I/O_8 Left	I/O_0–I/O_8Right	Status
No action	1	1	Semaphore free
Left port writes 0 to semaphore	0	1	Left port has semaphore token
Right port writes 0 to semaphore	0	1	No change. Right side has no write access to semaphore
Left port writes 1 to semaphore	1	0	Right port obtains semaphore token
Left port writes 0 to semaphore	1	0	No change. Left port has no write access to semaphore
Right port writes 1 to semaphore	0	1	Left port obtains semaphore token
Left port writes 1 to semaphore	1	1	Semaphore free
Right port writes 0 to semaphore	1	0	Right port has semaphore token
Right port writes 1 to semaphore	1	1	Semaphore free
Left port writes 0 to semaphore	0	1	Left port has semaphore token
Left port writes 1 to semaphore	1	1	Semaphore free

Maximum Ratings

Exceeding maximum ratings [4] may shorten the useful life of the device. User guidelines are not tested.

Storage temperature ..... –65 °C to +150 °C

Ambient temperature with power applied ..... –55 °C to +125 °C

Supply voltage to ground potential ..... –0.5 V to +4.6 V

DC voltage applied to outputs in high Z State ..... –0.5 V to V_{CC} + 0.5 V

DC input voltage ..... –0.5 V to V_{CC} + 0.5 V

Output current into outputs (LOW) ..... 20 mA

Static discharge voltage ..... > 1100 V

Latch-up current ..... > 200 mA

Operating Range

Range	Ambient Temperature	V_{CC}
Commercial	0 °C to +70 °C	3.3 V ± 300 mV
Industrial [5]	–40 °C to +85 °C	3.3 V ± 300 mV

Electrical Characteristics

Over the Operating Range

Parameter	Description		CY7C009V									Unit
			-15			-20			-25			
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
V_{OH}	Output HIGH voltage (V_{CC} = Min, I_{OH} = –4.0 mA)		2.4	–	–	2.4	–	–	2.4	–	–	V
V_{OL}	Output LOW voltage (V_{CC} = Min, I_{OH} = +4.0 mA)		–		0.4	–		0.4	–		0.4	V
V_{IH}	Input HIGH voltage		2.2		–	2.2		–	2.2		–	V
V_{IL}	Input LOW voltage		–		0.8	–		0.8	–		0.8	V
I_{IX}	Input leakage current		–5		5	–5		5	–5		5	µA
I_{OZ}	Output leakage current		–10		10	–10		10	–10		10	µA
I_{CC}	Operating current (V_{CC} = Max, I_{OUT} = 0 mA) outputs disabled	Commercial	–	125	185	–	120	175	–	115	165	mA
		Industrial		–			140	195		–		mA
I_{SB1}	Standby current (both ports TTL level) $\overline{CE}_L$ and $\overline{CE}_R \geq V_{IH}$, f = f_{MAX}	Commercial		35	50		35	45		30	40	mA
		Industrial		–			45	55		–		mA
I_{SB2}	Standby current (one port TTL level) $\overline{CE}_L$ | $\overline{CE}_R \geq V_{IH}$, f = f_{MAX}	Commercial		80	120		75	110		65	95	mA
		Industrial		–			85	120		–		mA
I_{SB3}	Standby current (both ports CMOS level) $\overline{CE}_L$ and $\overline{CE}_R \geq V_{CC}$ – 0.2 V, f = 0	Commercial		10	250		10	250		10	250	µA
		Industrial		–			10	250		–		µA
I_{SB4}	Standby current (one port CMOS level) $\overline{CE}_L$ | $\overline{CE}_R \geq V_{IH}$, f = f_{MAX} [6]	Commercial		75	105		70	95		60	80	mA
		Industrial		–			80	105		–		mA

Notes

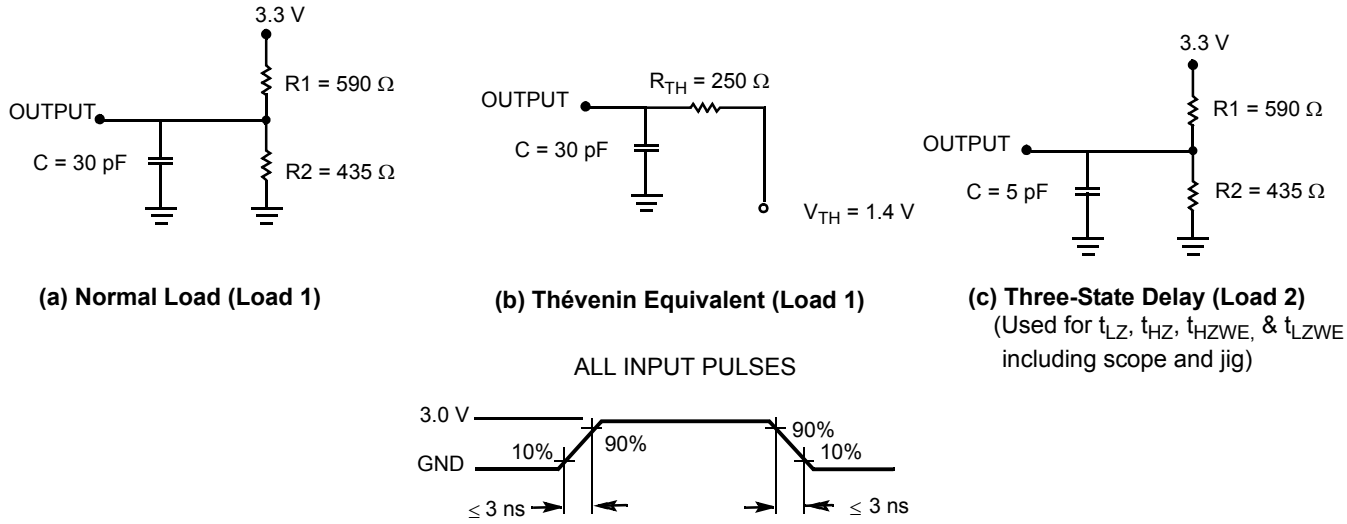
4. The voltage on any input or I/O pin cannot exceed the power pin during power-up.
5. Industrial parts are available in CY7C009V.
6. $f_{MAX} = 1/t_{RC}$ = All inputs cycling at f = $1/t_{RC}$ (except output enable). f = 0 means no address or control lines change. This applies only to inputs at CMOS level standby I_{SB3}.

Capacitance

Parameter [7]	Description	Test Conditions	Max	Unit
C_{IN}	Input capacitance	T_A = 25 °C, f = 1 MHz, V_{CC} = 3.3 V	10	pF
C_{OUT}	Output capacitance		10	pF

AC Test Loads and Waveforms

Figure 2. AC Test Loads and Waveforms



(a) Normal Load (Load 1)

(b) Thévenin Equivalent (Load 1)

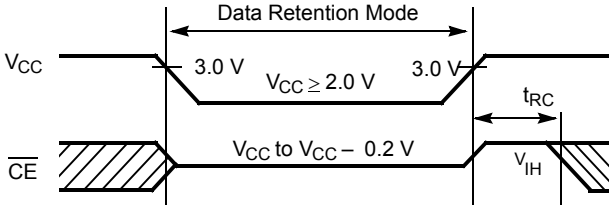
(c) Three-State Delay (Load 2)
(Used for t_{LZ}, t_{HZ}, t_{HZWE}, & t_{LZWE} including scope and jig)

Data Retention Mode

The CY7C009V is designed with battery backup in mind. Data retention voltage and supply current are guaranteed over temperature. The following rules ensure data retention:

1. Chip enable ($\overline{CE}$) must be held HIGH during data retention, within V_{CC} to V_{CC} – 0.2 V.
2. $\overline{CE}$ must be kept between V_{CC} – 0.2 V and 70% of V_{CC} during the power-up and power-down transitions.
3. The RAM can begin operation > t_{RC} after V_{CC} reaches the minimum operating voltage (3.0 V).

Timing



Parameter	Test Conditions [8]	Max	Unit
ICC_{DR1}	@ VCC_{DR} = 2 V	50	µA

Notes
7. Tested initially and after any design or process changes that may affect these parameters.
8. $\overline{CE}$ = V_{CC}, V_{in} = GND to V_{CC}, T_A = 25 °C. This parameter is guaranteed but not tested.

Switching Characteristics

Over the Operating Range

Parameter [9]	Description	CY7C009V						Unit
		-15		-20		-25		
		Min	Max	Min	Max	Min	Max	
READ CYCLE								
t_{RC}	Read cycle time	15	–	20	–	25	–	ns
t_{AA}	Address to data valid	–	15	–	20	–	25	ns
t_{OHA}	Output hold from address change	3	–	3	–	3	–	ns
t_{ACE}[10]	$\overline{CE}$ LOW to data valid	–	15	–	20	–	25	ns
t_{DOE}	$\overline{OE}$ LOW to data valid	–	10	–	12	–	13	ns
t_{LZOE}[11, 12, 13]	$\overline{OE}$ LOW to low Z	3	–	3	–	3	–	ns
t_{HZOE}[11, 12, 13]	$\overline{OE}$ HIGH to high Z	–	10	–	12	–	15	ns
t_{LZCE}[11, 12, 13]	$\overline{CE}$ LOW to low Z	3	–	3	–	3	–	ns
t_{HZCE}[11, 12, 13]	$\overline{CE}$ HIGH to high Z	–	10	–	12	–	15	ns
t_{PU}[13]	$\overline{CE}$ LOW to power-up	0	–	0	–	0	–	ns
t_{PD}[13]	$\overline{CE}$ HIGH to power-down	–	15	–	20	–	25	ns
t_{ABE}[10]	Byte enable access time	–	15	–	20	–	25	ns
WRITE CYCLE								
t_{WC}	Write cycle time	15	–	20	–	25	–	ns
t_{SCE}[10]	$\overline{CE}$ LOW to write end	12	–	16	–	20	–	ns
t_{AW}	Address valid to write end	12	–	16	–	20	–	ns
t_{HA}	Address hold from write end	0	–	0	–	0	–	ns
t_{SA}[10]	Address set-up to write start	0	–	0	–	0	–	ns
t_{PWE}	Write pulse width	12	–	17	–	22	–	ns
t_{SD}	Data set-up to write end	10	–	12	–	15	–	ns
t_{HD}	Data hold from write end	0	–	0	–	0	–	ns
t_{HZWE}[12, 13]	R/$\overline{W}$ LOW to high Z	–	10	–	12	–	15	ns
t_{LZWE}[12, 13]	R/$\overline{W}$ HIGH to low Z	3	–	3	–	3	–	ns
t_{WDD}[14]	Write pulse to data delay	–	30	–	40	–	50	ns
t_{DDD}[14]	Write data valid to read data valid	–	25	–	30	–	35	ns

Notes

9. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_{OL}/I_{OH} and 30 pF load capacitance.
10. To access RAM, $\overline{CE}$ = L, $\overline{SEM}$ = H. To access semaphore, $\overline{CE}$ = H and $\overline{SEM}$ = L. Either condition must be valid for the entire t_{SCE} time.
11. At any given temperature and voltage condition for any given device, t_{HZCE} is less than t_{LZCE} and t_{HZOE} is less than t_{LZOE}.
12. Test conditions used are Load 2.
13. This parameter is guaranteed by design, but it is not production tested.For information on port-to-port delay through RAM cells from writing port to reading port, refer to Read Timing with Busy waveform.
14. For information on port-to-port delay through RAM cells from writing port to reading port, refer to Read Timing with Busy waveform.

Switching Characteristics *(continued)*

Over the Operating Range

Parameter [9]	Description	CY7C009V						Unit
		-15		-20		-25		
		Min	Max	Min	Max	Min	Max	
BUSY TIMING [15]								
t_{BLA}	$\overline{BUSY}$ LOW from address match	–	15	–	20	–	20	ns
t_{BHA}	$\overline{BUSY}$ HIGH from address mismatch	–	15	–	20	–	20	ns
t_{BLC}	$\overline{BUSY}$ LOW from $\overline{CE}$ LOW	–	15	–	20	–	20	ns
t_{BHC}	$\overline{BUSY}$ HIGH from $\overline{CE}$ HIGH	–	15	–	16	–	17	ns
t_{PS}	Port set-up for priority	5	–	5	–	5	–	ns
t_{WB}	R/$\overline{W}$ HIGH after $\overline{BUSY}$ (Slave)	0	–	0	–	0	–	ns
t_{WH}	R/$\overline{W}$ HIGH after $\overline{BUSY}$ HIGH (Slave)	13	–	15	–	17	–	ns
t_{BDD} [16]	$\overline{BUSY}$ HIGH to data valid	–	15	–	20	–	25	ns
INTERRUPT TIMING [15]								
t_{INS}	$\overline{INT}$ set time	–	15	–	20	–	20	ns
t_{INR}	$\overline{INT}$ reset time	–	15	–	20	–	20	ns
SEMAPHORE TIMING								
t_{SOP}	SEM flag update pulse ($\overline{OE}$ or $\overline{SEM}$)	10	–	10	–	12	–	ns
t_{SWRD}	SEM flag write to read time	5	–	5	–	5	–	ns
t_{SPS}	SEM flag contention window	5	–	5	–	5	–	ns
t_{SAA}	SEM address access time	–	15	–	20	–	25	ns

Notes
15. Test conditions used are Load 1.
16. t_{BDD} is a calculated parameter and is the greater of t_{WDD}–t_{PWE} (actual) or t_{DDD}–t_{SD} (actual).

Switching Waveforms

Figure 3. Read Cycle No.1 (Either Port Address Access) [17, 18, 19]

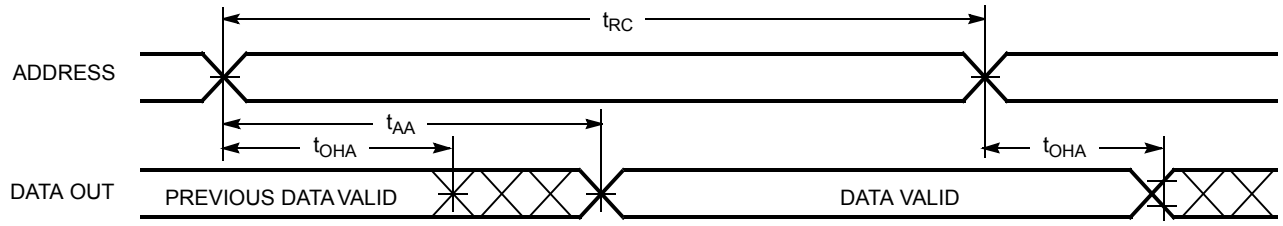


Figure 4. Read Cycle No.2 (Either Port $\overline{CE}$/$\overline{OE}$ Access) [17, 20, 21]

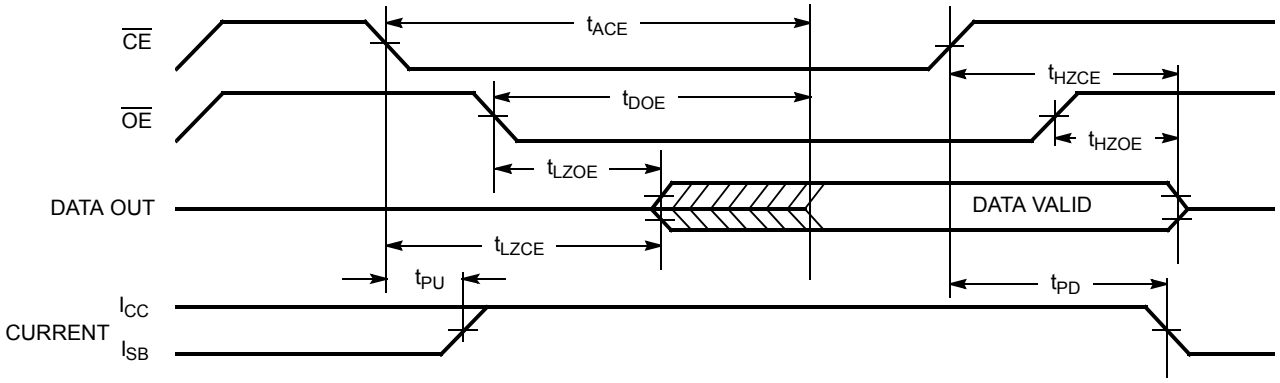
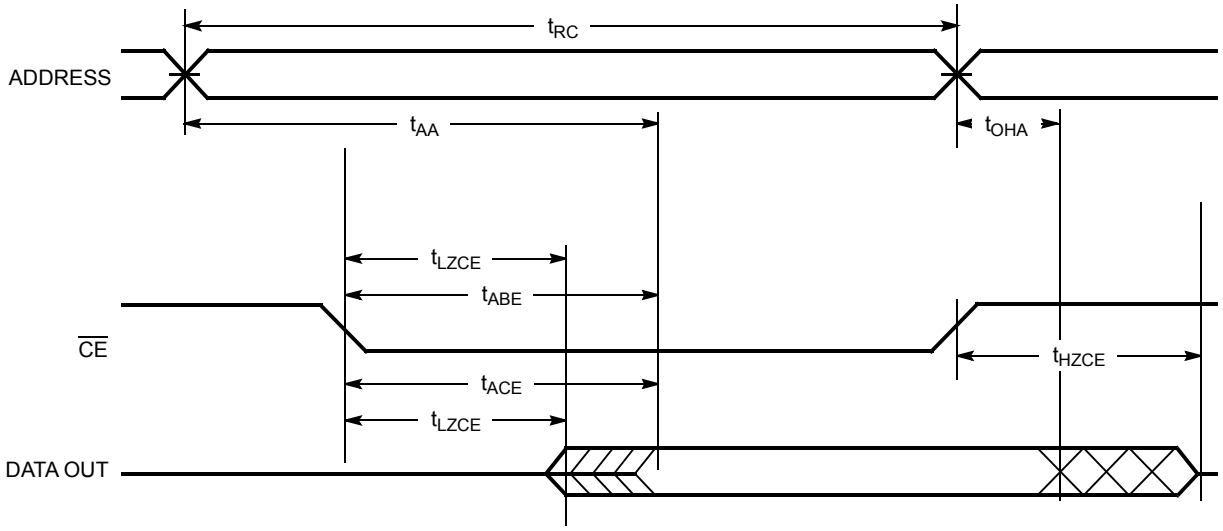


Figure 5. Read Cycle No. 3 (Either Port) [17, 19, 20, 21]



Notes
17. R/$\overline{W}$ is HIGH for read cycles.
18. Device is continuously selected $\overline{CE}$ = V_{IL}. This waveform cannot be used for semaphore reads.
19. $\overline{OE}$ = V_{IL}.
20. Address valid prior to or coincident with $\overline{CE}$ transition LOW.
21. To access RAM, $\overline{CE}$ = V_{IL}, $\overline{SEM}$ = V_{IH}. To access semaphore, $\overline{CE}$ = V_{IH}, $\overline{SEM}$ = V_{IL}.

Switching Waveforms *(continued)*

Figure 6. Write Cycle No. 1 (R/$\overline{W}$ Controlled Timing) [22, 23, 24, 25]

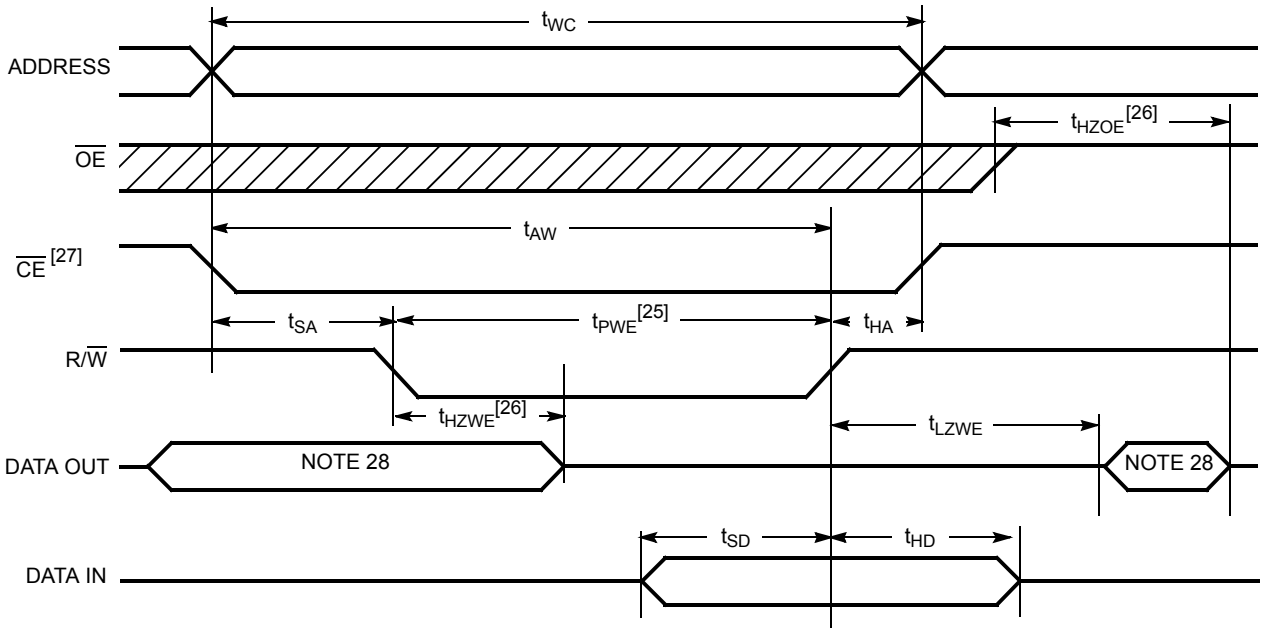
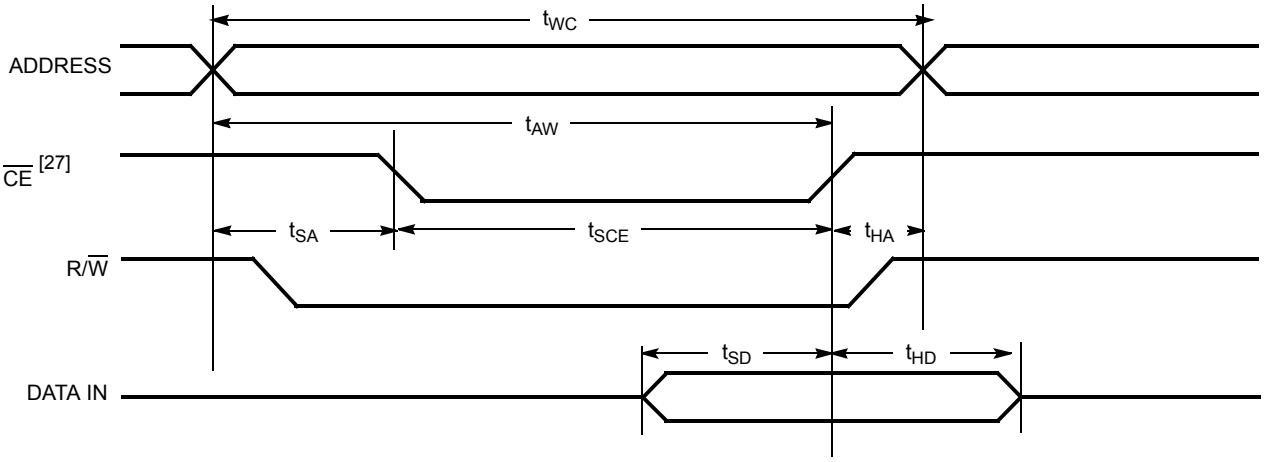


Figure 7. Write Cycle No. 2 ($\overline{CE}$ Controlled Timing) [22, 23, 24, 29]



Notes

22. R/$\overline{W}$ must be HIGH during all address transitions.
23. A write occurs during the overlap (t_{SCE} or t_{PWE}) of a LOW $\overline{CE}$ or $\overline{SEM}$.
24. t_{HA} is measured from the earlier of $\overline{CE}$ or R/$\overline{W}$ or ($\overline{SEM}$ or R/$\overline{W}$) going HIGH at the end of write cycle.
25. If $\overline{OE}$ is LOW during a R/$\overline{W}$ controlled write cycle, the write pulse width must be the larger of t_{PWE} or (t_{HZWE} + t_{SD}) to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{SD}. If $\overline{OE}$ is HIGH during an R/$\overline{W}$ controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified t_{PWE}.
26. Transition is measured ±500 mV from steady state with a 5 pF load (including scope and jig). This parameter is sampled and not 100% tested.
27. To access RAM, $\overline{CE}$ = V_{IL}, $\overline{SEM}$ = V_{IH}.
28. During this period, the I/O pins are in the output state, and input signals must not be applied.
29. If the $\overline{CE}$ or $\overline{SEM}$ LOW transition occurs simultaneously with or after the R/$\overline{W}$ LOW transition, the outputs remain in the high-impedance state.

Switching Waveforms *(continued)*

Figure 8. Semaphore Read after Write Timing, Either Side [30]

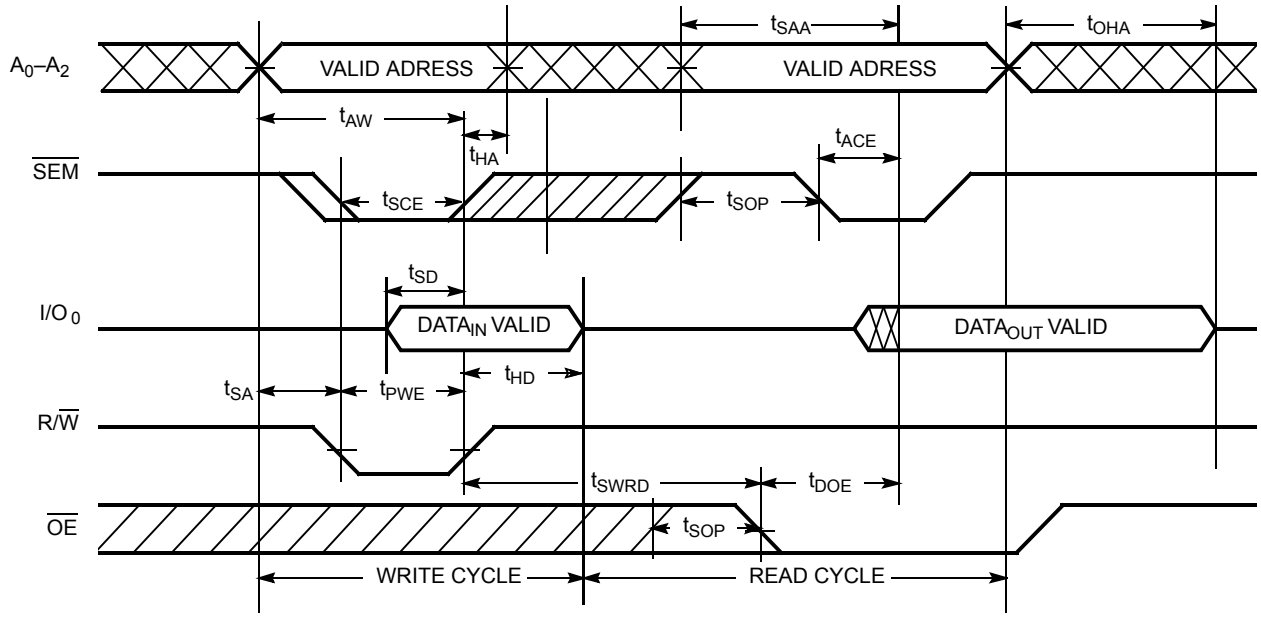
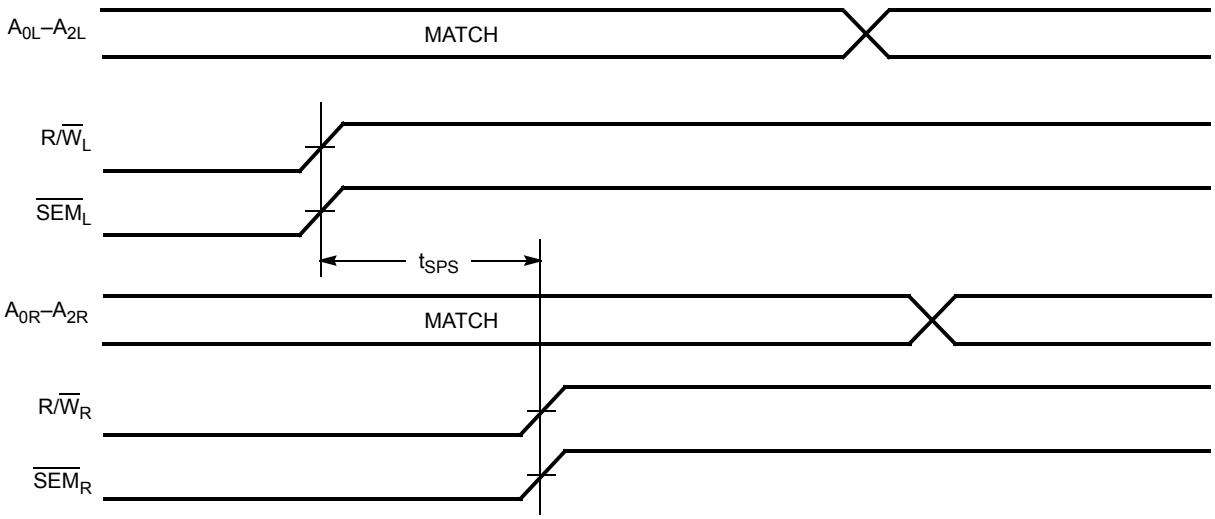


Figure 9. Timing Diagram of Semaphore Contention [31, 32, 33]



Notes
30. $\overline{CE}$ = HIGH for the duration of the above timing (both write and read cycle).
31. $I/O_{0R} = I/O_{0L}$ = LOW (request semaphore); $\overline{CE}_R = \overline{CE}_L$ = HIGH.
32. Semaphores are reset (available to both ports) at cycle start.
33. If t_{SPS} is violated, the semaphore will definitely be obtained by one side or the other, but which side will get the semaphore is unpredictable.

Switching Waveforms *(continued)*

Figure 10. Timing Diagram of Read with $\overline{BUSY}$ (M/$\overline{S}$ = HIGH) [34]

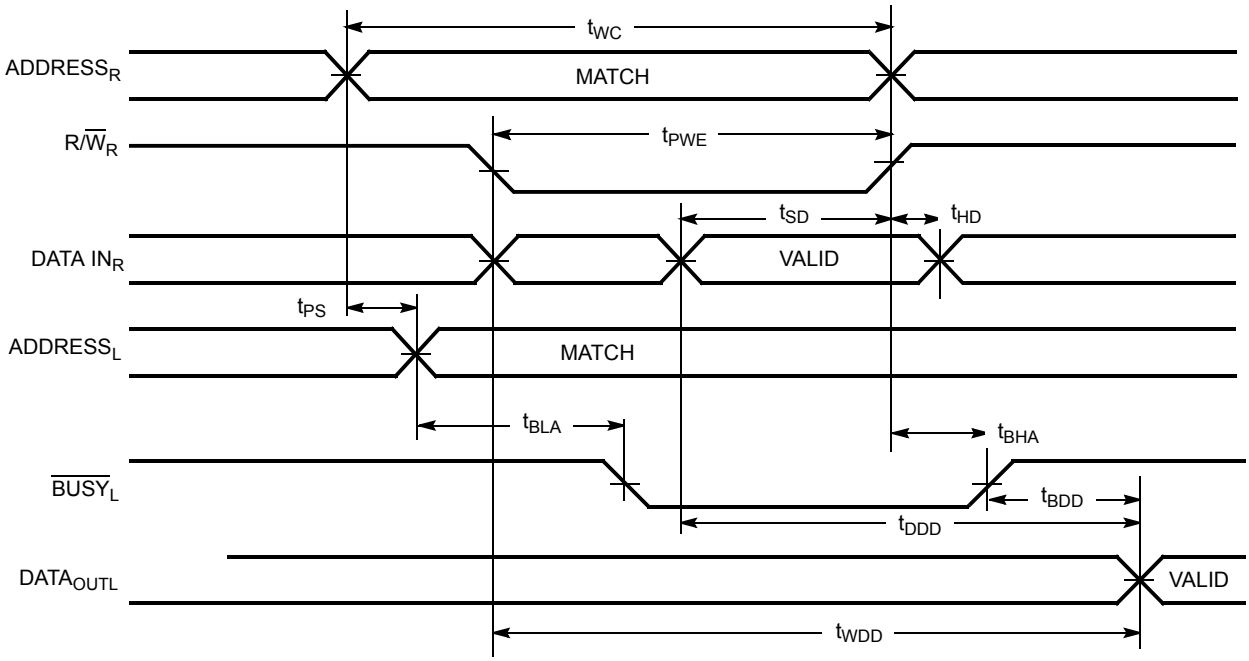
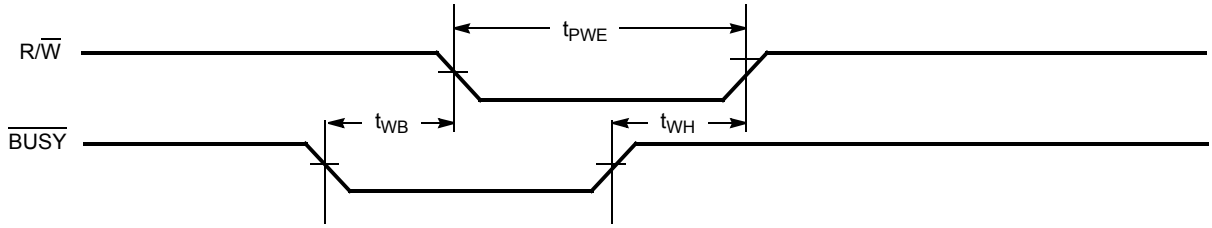


Figure 11. Write Timing with Busy Input (M/$\overline{S}$ = LOW)

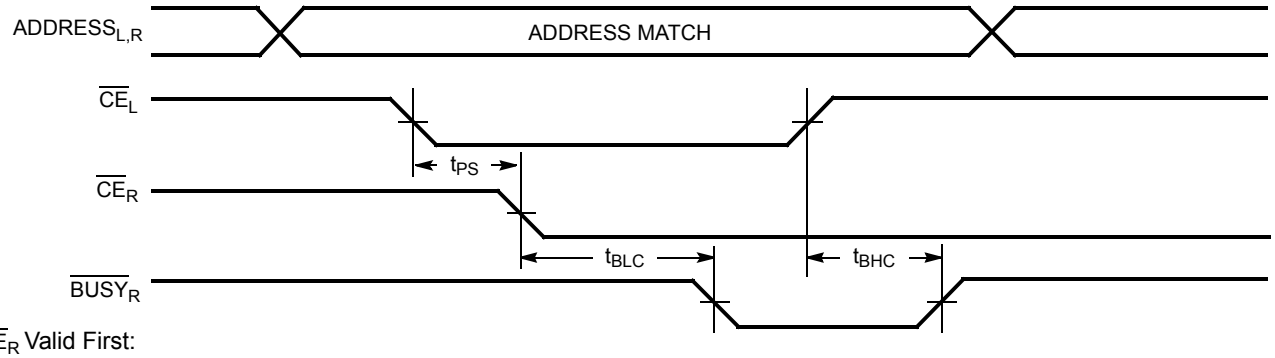


Note
34. $\overline{CE}_L$ = $\overline{CE}_R$ = LOW.

Switching Waveforms *(continued)*

Figure 12. Busy Timing Diagram No. 1 ($\overline{CE}$ Arbitration) [35]

$\overline{CE}_L$ Valid First:



$\overline{CE}_R$ Valid First:

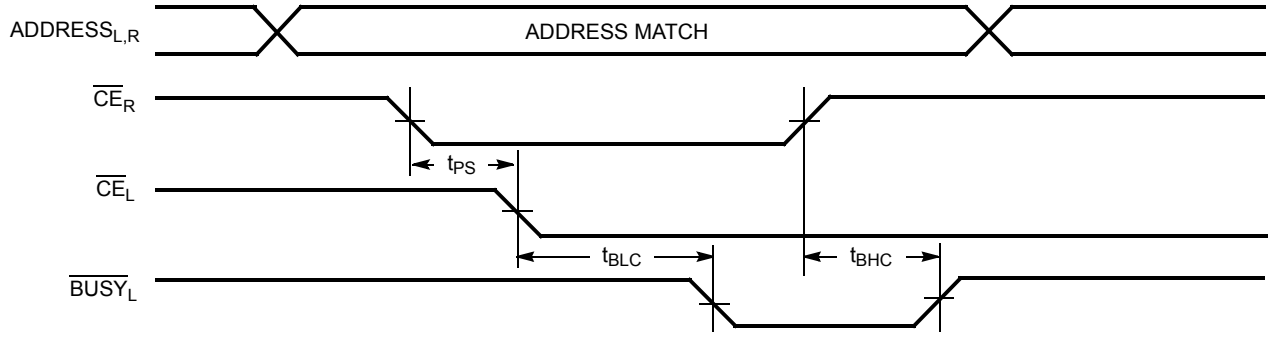
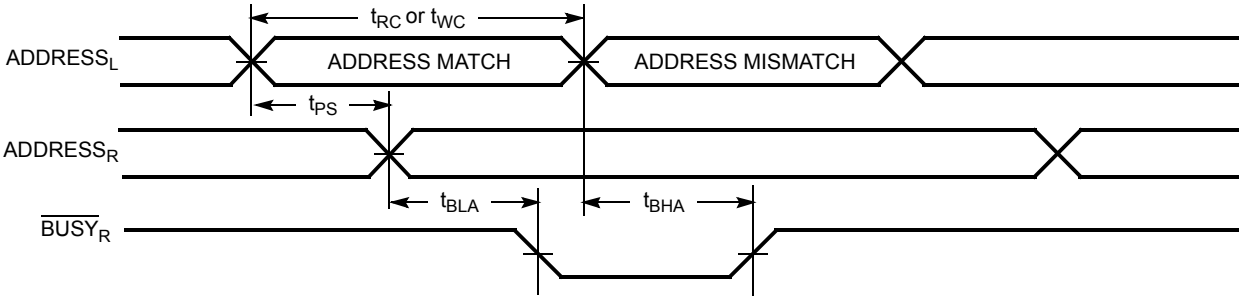
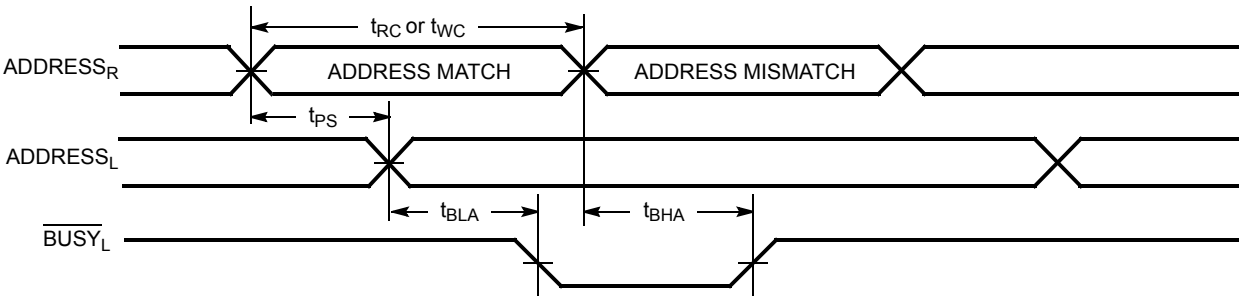


Figure 13. Busy Timing Diagram No. 2 (Address Arbitration) [35]

Left Address Valid First:



Right Address Valid First:

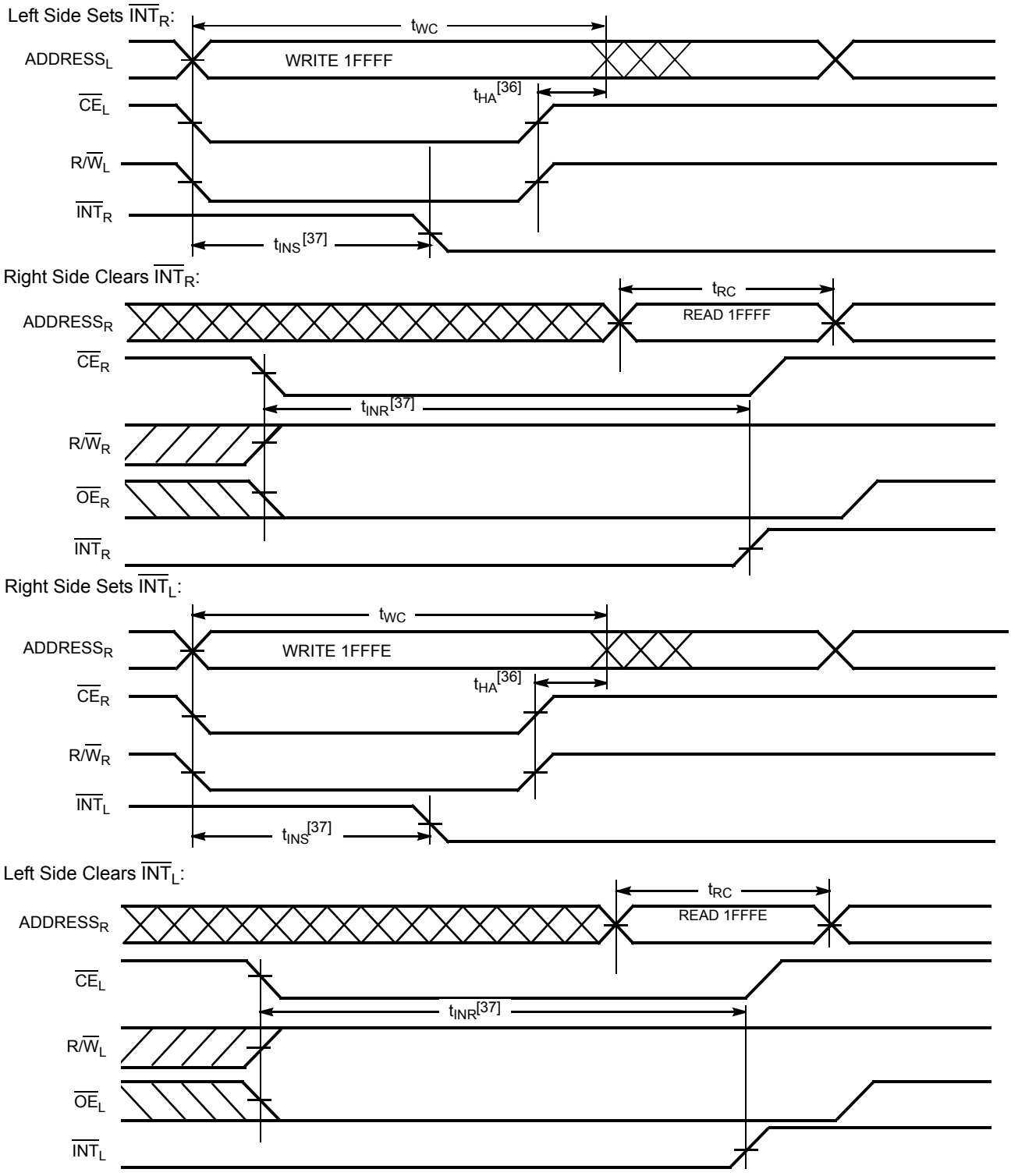


Note

35. If t_{PS} is violated, the busy signal will be asserted on one side or the other, but there is no guarantee to which side $\overline{BUSY}$ will be asserted.

Switching Waveforms *(continued)*

Figure 14. Interrupt Timing Diagrams



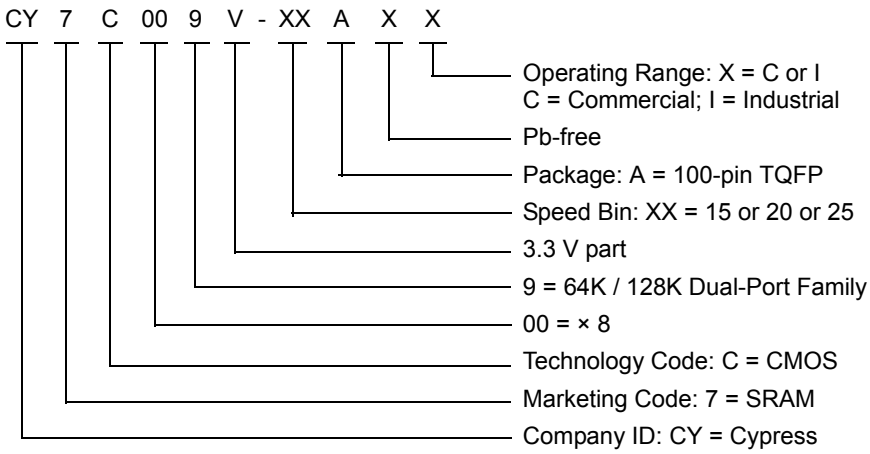
Notes
36. t_{HA} depends on which enable pin ($\overline{CE}_L$ or $R/\overline{W}_L$) is deasserted first.
37. t_{INS} or t_{INR} depends on which enable pin ($\overline{CE}_L$ or $R/\overline{W}_L$) is asserted last.

Ordering Information

128K × 8, 3.3 V Asynchronous Dual-Port SRAM

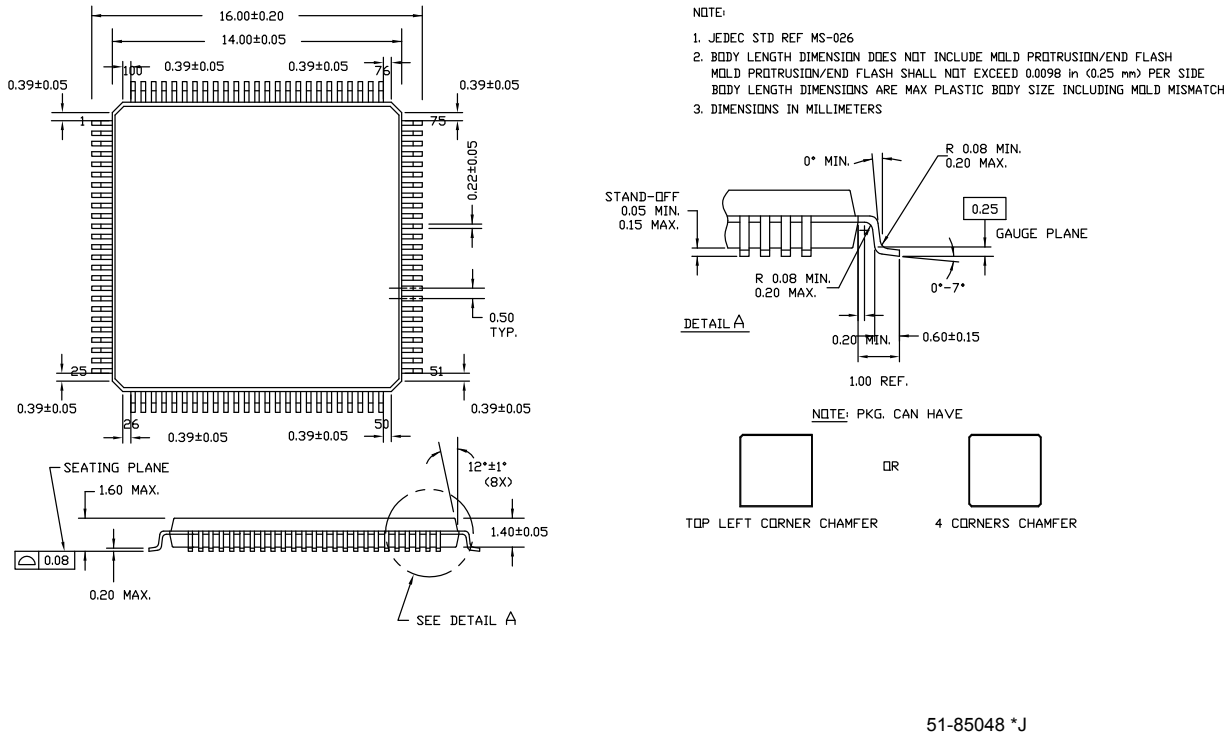
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C009V-15AXC	A100	100-pin TQFP Pb-free	Commercial
20	CY7C009V-20AXI	A100	100-pin TQFP Pb-free	Industrial
25	CY7C009V-25AXC	A100	100-pin TQFP Pb-free	Commercial

Ordering Code Definitions



Package Diagram

Figure 15. 100-pin TQFP (14 × 14 × 1.4 mm) A100SA Package Outline, 51-85048



51-85048 *J

Acronyms

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
$\overline{CE}$	Chip Enable
I/O	Input/Output
$\overline{INT}$	Interrupt
$\overline{OE}$	Output Enable
$\overline{SEM}$	Semaphore
SRAM	Static Random Access Memory
TQFP	Thin Quad Flat Pack
TTL	Transistor-Transistor Logic

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
µA	microampere
mA	milliampere
ms	millisecond
mV	millivolt
ns	nanosecond
pF	picofarad
V	volt
W	watt

Document History Page

Document Title: CY7C009V, 3.3 V, 128K × 8 Dual-Port Static RAM Document Number: 38-06044				
Rev.	**ECN No.**	**Issue Date**	**Orig. of Change**	**Description of Change**
**	110192	09/29/01	SZV	Change from Spec number: 38-00669 to 38-06044
*A	113541	04/15/02	OOR	Updated Pin Configurations (Changed pin 85 from $\overline{\text{BUSY}}$L to $\overline{\text{BUSY}}$R in the figure “100-pin TQFP (Top View)” (corresponding to CY7C018V/019V)).
*B	122294	12/27/02	RBI	Updated Maximum Ratings: Added Note 4 and referred the same note in “maximum ratings”.
*C	393440	See ECN	YIM	Added Pb-free Logo Updated Ordering Information (Added Pb-free parts (CY7C008V-25AXC, CY7C009V-15AXC, CY7C009V-20AXI, CY7C009V-25AXC, CY7C019V-15AXC, CY7C019V-20AXC, CY7C019V-20AXI, CY7C019V-25AXC)).
*D	2896038	03/19/10	RAME	Updated Ordering Information (Removed inactive parts). Updated Package Diagram.
*E	3081242	11/09/2010	ADMU	Added Ordering Code Definitions. Added Acronyms and Units of Measure. Minor edits. Updated to new template.
*F	3816114	11/19/2012	SMCH	Updated Document Title to read “CY7C009V, 3.3 V 128 K × 8 Dual-Port Static RAM”. Updated Features (Removed CY7C008V, CY7C018V, CY7C019V related information). Updated Logic Block Diagram (Removed CY7C008V, CY7C018V, CY7C019V related information, removed Notes “I/O_0–I/O_7 for × 8 devices; I/O_0–I/O_8 for × 9 devices.” and “A_0–A_{15} for 64K devices; A_0–A_{16} for 128K.” and their references in Logic Block DIagram). Updated Functional Description (Removed CY7C008V, CY7C018V, CY7C019V related information). Updated Selection Guide (Removed CY7C008V, CY7C018V, CY7C019V related information). Updated Pin Configurations (Updated Figure 1 (Removed CY7C008V related information, removed the Note “This pin is NC for CY7C008V.” and its reference in the same figure), removed the figure “100-pin TQFP (Top View)”, removed the Note “This pin is NC for CY7C018V.”). Updated Pin Definitions (Removed CY7C008V, CY7C018V, CY7C019V related information). Updated Architecture (Removed CY7C008V, CY7C018V, CY7C019V related information). Updated Functional Overview (Updated Interrupts (Removed CY7C008V, CY7C018V, CY7C019V related information), updated Busy (Removed CY7C008V, CY7C018V, CY7C019V related information), updated Semaphore Operation (Removed CY7C008V, CY7C018V, CY7C019V related information), updated Table 2 (Removed CY7C008V, CY7C018V, CY7C019V related information), removed the Note “$A_{0L–16L}$ and $A_{0R–16R}$, 1FFFF/1FFFE for the CY7C009V/19V.” and its reference in the same table)). Updated Operating Range (Updated Note 5 (Removed CY7C019V related information)). Updated Electrical Characteristics (Removed CY7C008V, CY7C018V, CY7C019V related information, removed the Note “Industrial parts are available in CY7C009V and CY7C019V only.” and its reference in Electrical Characteristics).

Document History Page *(continued)*

Document Title: CY7C009V, 3.3 V, 128K × 8 Dual-Port Static RAM Document Number: 38-06044				
Rev.	**ECN No.**	**Issue Date**	**Orig. of Change**	**Description of Change**
*F (cont.)	3816114	11/19/2012	SMCH	Updated Data Retention Mode (Removed CY7C008V, CY7C018V, CY7C019V related information). Updated Switching Characteristics (Removed CY7C008V, CY7C018V, CY7C019V related information, updated Note 10 (Removed $\overline{UB}$ = L)). Updated Switching Waveforms (Updated Figure 14 (Removed CY7C019V related information)). Updated Package Diagram (spec 51-85048 (Changed revision from *D to *G)).
*G	4194765	11/18/2013	SMCH	Updated Pin Definitions: Replaced "$\overline{CE}_R$, CE_{1R}" with "$\overline{CE}_{0R}$, CE_{1R}" in "Right Port" column. Updated Switching Waveforms: Updated Figure 14. Updated Package Diagram: spec 51-85048 – Changed revision from *G to *H. Updated to new template. Completing Sunset Review.
*H	4580622	11/26/2014	SMCH	Updated Functional Description: Added "For a complete list of related documentation, click here." at the end. Updated Package Diagram: spec 51-85048 – Changed revision from *H to *I.
*I	5500204	10/28/2016	NILE	Updated Package Diagram: spec 51-85048 – Changed revision from *I to *J. Updated to new template. Completing Sunset Review.
*J	6001957	12/21/2017	AESATMP9	Updated logo and copyright.

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